FFT Spectrum Analyzers

SR780 — 100 kHz 2-channel dynamic signal analyzer



- · DC to 102.4 kHz bandwidth
- 90 dB dynamic range
- · Low-distortion synthesized source
- 145 dB dynamic range in swept-sine mode
- Real-time octave analysis
- Up to 32 Mbyte memory
- · GPIB and RS-232 interfaces

• SR780 ... \$9950 (U.S. list)

SR780 Dynamic Signal Analyzer

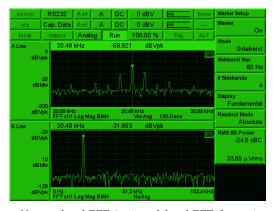
The SR780 Dynamic Signal Analyzer combines high performance and low cost in a full-featured package. It offers 102.4 kHz dual-channel FFTs with 90 dB dynamic range, 145 dB dynamic range swept-sine measurements, real-time ANSI standard octave analysis, waterfall displays, and transient capture for less than half the cost of other similarly equipped analyzers.

Spectrum Analysis

The SR780 delivers true two-channel 102.4 kHz FFT performance. Its fast 32-bit floating-point DSP processor gives the SR780 a 102.4 kHz real-time rate with both channels selected. Two precision 16-bit ADCs provide a 90 dB dynamic range in FFT mode. Selectable 100 to 800 line analysis optimizes time and frequency resolution, and you can zoom in on any portion of the 102.4 kHz range with a frequency span down to 191 mHz.

The SR780's unique architecture lets the two displays function independently. You can choose separate frequency spans, starting frequencies, number of FFT lines, or averaging modes for each display. So it's easy to look at a wideband display and zoom in on a specific feature simultaneously. The SR780 lets you select from two sampling rates: 256 kHz or 262 kHz, so frequency spans come out in either a binary (102.4 kHz, 51.2 kHz, ...) or decimal (100 kHz, 50 kHz, 25 kHz, ...) sequence depending on your requirements.





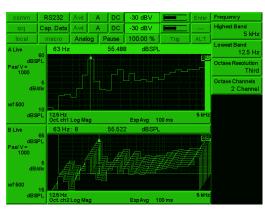
Narrow band FFT (top), wideband FFT (bottom)

Flexible Averaging

Several averaging choices are provided. RMS averaging reduces signal fluctuations, while vector averaging minimizes noise from synchronous signals. You can choose linear averaging (stable averaging) for fixed signals, or exponential averaging to track drifting features. Because the SR780's 102.4 kHz real-time bandwidth lets it take data seamlessly, vector averaging can be selected for any signal that's repetitive within the time record—no trigger is necessary.

Transducer Units

Automatic unit conversion makes translating accelerometer data easy. You can enter your accelerometer conversions directly in V/EU, EU/V or dB (1 V/EU). The SR780 will display results in units of meters, inches, mil, g, kg, lbs., N, dynes, pascals, bars or dBSPL. Accelerometer data is automatically converted to velocity or displacement units. Built-in ICP power means you won't need an external power supply for your accelerometer.



Octave analysis

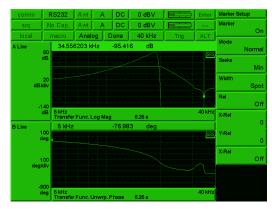
Octave Analysis

Real-time octave analysis, at frequencies up to 40 kHz (single channel) or 20 kHz (dual channel), is standard in the SR780.

Octave analysis is fully compliant with ANSI and IEC standards. Full octave, 1/3 octave, and 1/12 octave analysis are all available. Switchable analog A-weighting filters, as well as built-in user math weighting functions (A, B and C), are included. Octave averaging choices include exponential time averaging, linear time averaging, peak hold, and equal confidence averaging. IEC 651-1979 Type 0 compliant peak hold, impulse, fast and slow sound level measurements are all calculated.

Swept-Sine Analysis

Swept-sine analysis is used for measurements involving high dynamic range or wide frequency intervals, and is also a



Swept-sine Bode plot of LPF response

standard feature of the SR780. Selectable auto-ranging optimizes the input range at each point in the measurement, providing up to 145 dB of dynamic range. Auto-ranging can be used with source auto-leveling to maintain a constant input or output level at the device under test. To ensure the fastest sweeps possible, auto-resolution can also be selected, providing a variable scan speed tailored precisely to the signal being measured.

User Math

User-defined math functions are available in all measurement groups. Equations are created from time or frequency data,



User math



stored files, constants, or a rich array of supplied operations including the arithmetic functions, FFT, inverse FFT, $j\omega$, $d/d\omega$, exp, $\ln x$ and many others. Unlike many analyzers, the SR780's measurement rate isn't reduced when user math is selected. For instance, the function exp(ln(conj(avg.(FFT2/FFT1))) can be calculated with a 50 kHz real-time bandwidth.

Source

Six source types are available: low distortion (-80 dBc) single or two-tone sine waves, chirp, white noise, pink noise, and arbitrary waveforms. The chirp and noise sources can both be bursted to provide a source that's active only over a selected portion of the time record for FFT measurements, or to provide an impulsive noise source for acoustic measurements. The digitally synthesized source provides output levels from 0.1 mV to 5 V, and delivers up to 100 mA of current.

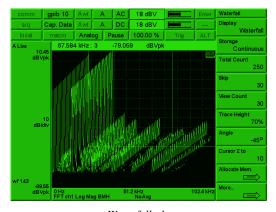
Arbitrary waveform capability is standard on the SR780. The arbitrary source can be used to playback a section of a captured waveform, play a selected FFT time record, or upload a custom waveform.

Capture

The SR780 comes standard with 2 Msamples capture memory. Waveforms can be captured at 262 kHz or any sub-multiple of 262 kHz, allowing you to select the sample rate and capture length that's right for your data. Once captured, any portion of the signal can be played back in FFT or Octave mode. The convenient "AutoPan" feature lets you display the measurement results synchronously with the corresponding portion of the capture buffer to easily identify important features. An optional memory expansion module lets you extend the SR780's capture depth to 8 Msamples—that's almost 30 seconds of capture at the maximum sampling rate.

Waterfall

All Octave and FFT measurements can be stored in the SR780's 2k-deep waterfall buffers. Waterfall storage is selectable as every nth time record for FFT measurements, or



Waterfall plot

you can select a storage interval in seconds (down to 4 ms) for octave measurements. While displaying waterfalls, you can adjust the skew angle to reveal important features, or change the baseline threshold to eliminate low-level clutter. Any z-axis slice or x-axis record can be saved to disk or displayed separately for individual analysis.

Analysis

The SR780 includes a wide variety of analysis features. Marker analysis lets you use the marker to measure the power contained in the harmonics, sidebands or within a given band of frequencies. THD, THD + N, sideband power relative to carrier, and total integrated power are calculated in real time and displayed on the screen. Marker statistics quickly calculate the maximum, minimum, mean and standard deviation of data at any point in the display.

A data table feature lets you display up to 100 selected data points in tabular format. Limit tables let you to define up to 100 upper and lower limit segments in each display for GO/NO-GO testing.

Output

The SR780's 3.5" disk drive, computer interfaces (GPIB and RS-232) and printer port provide flexibility when saving, printing and exporting data. Data can be saved in binary or ASCII formats, and displays can be printed/plotted to any of the ports or the disk drive. Supported formats include PCL (LaserJet/DeskJet), dot-matrix, postscript, HP-GL, PCX or GIF. Utilities are included to translate HP SDF files into SR780 format.



FFT Group Measurements

FFT, Time Record, Windowed Time, Time Capture, Transfer Function, Cross Spectrum, Coherence, Cross-Correlation, Auto-Correlation, Orbit, User Math

Octave Analysis Group Measurements

1/1, 1/3, 1/12 Octave, Time Capture, User Math, $L_{\rm eq}$, Impulse, Total Power

Swept-Sine Group Measurements

Spectrum, Transfer Function, Cross Spectrum, User Math

FFT Resolution

100, 200, 400, 800 lines

Views

Linear Magnitude, Log Magnitude, Magnitude Squared, Real Part, Imaginary Part, Phase, Unwrapped Phase, Nichols, Nyquist

Units

V, V^2 , V^2/Hz , V/\sqrt{Hz} , meters, inches, mils, g, kg, lbs., N, dynes, pascals, bars, SPL, user-defined engineering units

Displays

Single, Dual, Waterfall with Skew, Zoom and Pan

Averaging

RMS, Vector, Peak Hold, Linear, Exponential, Equal Confidence (Octave), Preview Time Record

Triggering

Continuous, Internal, External (Analog or TTL), Source, Auto/Manual Arming

Source Outputs

Sine, Two-Tone, Swept-Sine, White/Pink Noise, Burst Noise, Chirp, Burst Chirp, and Arbitrary

Windows

Hanning, Blackman-Harris, Flat-Top, Kaiser, Force/Exponential, User-Defined, ±T/2, ±T/4, T/2, Uniform

User Math

+, -, ×, ÷, Conjugate, Magnitude/Phase, Real/Imaginary, Sqrt, FFT, Inverse FFT, j ω , Log, Exp, d/dx, Group Delay, A-Weighting, B-Weighting, C-Weighting, x/x-1

Analysis

Harmonic, Band, Sideband, THD, THD + N, Limit Test, Data Table, Exceedance, Statistics

Time Capture

Captures time data for later analysis (FFT or Octave). Up to 2 Msamples (8 Msamples opt.) of data can be saved.

Storage

3.5", 1.44 Mbyte, DOS formatted disk. Save data and setups.

Hard Copy and Interfaces

Print to dot-matrix or PCL (LaserJet and DeskJet) printers. Plot to HP-GL or postscript plotters. Print/plot on-line (RS-232 serial, Centronics parallel or IEEE-488.2) or to disk file. EPS, GIF, PCX graphic formats also available for disk storage.

Help

Full, context-sensitive help screens for all SR780 features mean you will rarely have to refer to a printed manual. Hypertext links let you quickly switch between related help pages or instantly reference the remote command corresponding to any SR780 function. Use the help index to quickly locate help on any topic, jump to the online troubleshooting guide, browse a complete listing of the SR780's specifications, or examine a comprehensive description the SR780's remote commands.



SR780 rear panel

Ordering Information

SR780	Dynamic signal analyzer	\$9950
O780M1	8 Msample (32 Mbyte) memory	\$800
O780RM	Rack mount kit	\$85
CT100	SRS instrument cart	\$850



Specifications apply after 30 minutes warm-up and within two hours of last auto-offset. Measured with 400-line resolution and anti-alias filters enabled unless stated otherwise.

Measurement Groups

Group FFT, Octave Analysis, Swept-Sine

Frequency

Range 102.4 kHz or 100 kHz (both

displays have the same range)

FFT spans 195.3 mHz to 102.4 kHz or

> 191 mHz to 100 kHz. The two displays can have different spans

and start frequencies.

FFT resolution 100, 200, 400 or 800 lines

Real-time bandwidth 102.4 kHz (highest FFT span with

continuous data acquisition

and averaging)

25 ppm from 20 °C to 40 °C Accuracy

Dynamic Range

Dynamic range

FFT and Octave 90 dB typical, 80 dB guaranteed

Swept-Sine 145 dB

> Includes spurs, harmonic and intermodulation distortion and alias products. Excludes alias responses

at extremes of span.

Harmonic distortion < -80 dB (single tone in band)

Intermodulation dist. < -80 dB (two tones in band, each

less than -6.02 dBfs)

< -80 dBfsSpurious

< -80 dBfs (single tone outside of Alias responses

span, <0 dBfs, <1 MHz)

Full-span FFT noise

floor

−100 dBfs typical (input grounded, range > -30 dBV, Hanning window,

64 rms averages)

< -30 dBfs (FFT with Auto-Cal on) Residual DC response

Amplitude Accuracy

Single channel ± 0.2 dB (excluding windowing) Cross channel ± 0.05 dB (DC to 102.4 kHz)

> (transfer function meas., both inputs on same range, rms averaged)

Phase Accuracy

Single channel ±3.0 deg. relative to external TTL

> trigger (-50 dBfs to 0 dBfs, frequency <10.24 kHz, center of frequency bin, DC coupled). For Blackman-Harris, Hanning,

Flattop and Kaiser windows, phase is relative to a cosine wave at the center of the time record. For

Uniform, Force and Exponential windows, phase is relative to a cosine wave at the beginning of the

time record.

Cross channel ±0.5 deg. (DC to 51.2 kHz)

±1.0 deg. (DC to 102.4 kHz) (transfer function measurement, both inputs on the same input range,

vector averaged)

Signal Inputs

Number of inputs

Full-scale input range -50 dBV (3.16 mVp) to

+34 dBV (50 Vp) in 2 dB steps

Maximum input level 57 Vp

Single-ended (A), differential (A–B) Input configuration

Input impedance $1 \text{ M}\Omega + 50 \text{ pF}$ Shield to chassis

Floating mode: $1 \text{ M}\Omega + 0.01 \mu\text{F}$

Grounded mode: 50Ω

Shields are always grounded in

differential input (A-B)

Max. shield voltage 4 Vp

AC coupling 0.16 Hz cutoff frequency **CMRR**

90 dB at 1 kHz (input range < 0 dBV)

80 dB at 1 kHz (input range <10 dBV)

50 dB at 1 kHz (input range ≥10 dBV)

ICP signal Current source: 4.8 mA

Open circuit voltage: +26 V A-weight filter Type 0 tolerance, ANSI standard

S1.4-1983 (10 Hz to 25.6 kHz)

Crosstalk < -145 dB below signal (input to

> input and source to inputs, 50 Ω receiving input source impedance)

Input noise <10 nVrms/√Hz above 200 Hz

 $(<-160 \text{ dBVrms}/\sqrt{\text{Hz}})$

Trigger Input

External TTL

Modes Free Run, Internal, External, or

External TTL

Internal Level adjustable to ± 100 % of input

> scale. (Positive or negative slope) Min. trigger level: 5 % of input range

External Level adjustable to ± 5 V in 40 mV

steps. (Positive or negative slope)

Input impedance: 1 M Ω Max. input: ±5 V

Min. trigger level: 100 mV Requires TTL level to trigger

(low <0.7 V, high >3.0 V)

Measurement record is delayed up Post-trigger

to 8192 samples after the trigger.



Pre-trigger Measurement record starts up to

8192 samples prior to the trigger.

Transient Capture

Mode Continuous data recording
Maximum rate 262,144 samples/s for both inputs
Max. capture length 2 Msamples (single input)

8 Msamples with optional memory

Octave Analysis

Standards Conforms to ANSI std. S1.11-1986

Order 3 Type 1-D and IEC 225-1966

Frequency range Single channel:

1/1 Octave 0.125 Hz to 32 kHz 1/3 Octave 0.100 Hz to 40 kHz 1/12 Octave 0.091 Hz to 12.3 kHz

Two channels:

1/1 Octave 0.125 Hz to 16 kHz 1/3 Octave 0.100 Hz to 20 kHz 1/12 Octave 0.091 Hz to 6.17 kHz <0.2 dB (1 second stable average.

Accuracy <0.2 dB (1 second stable average, single tone at band center)

Dynamic range 80 dB (1/3 octave, 2 second stable average) per ANSI S1.11-1986

Sound level Impulse, Peak, Fast, Slow and L_{eq} per ANSI S1.4-1983 Type 0 and

IEC 651-1979 Type 0

Source Output

Amplitude range 0.1 mVp to 5 Vp

Amplitude resolution 0.1 mVp (output >500 mVp)

DC offset <10.0 mV (typ.)

Offset adjust ± 5 VDC (sine, two-tone)

Output impedance $<5 \Omega$, ± 100 mA peak output current

Sine Source

Amplitude accuracy ± 1 % of setting, 0 Hz to 102.4 kHz,

0.1 Vp to 5.0 Vp, Hi-Z load

Harmonics, sub-harm. 0.1 Vp to 5 Vp

& spurious < -80 dBc (fundamental <30 kHz)

< -75 dBc (fundamental <102 kHz)

Two-Tone Source

Amplitude accuracy ± 1 % of setting, 0 Hz to 102.4 kHz,

0.1 Vp to 5 Vp, Hi-Z load

Harmonics, sub-harm. < -80 dBc, 0.1 Vp to 2.5 Vp

White Noise Source

Time Record Continuous or burst

Bandwidth DC to 102.4 kHz or limited to span

Flatness <0.25 dBpp (typ.), <1.0 dBpp

(max.), 5000 rms averages

Pink Noise Source

Bandwidth DC to 102.4 kHz

Flatness <2.0 dBpp, 20 Hz to 20 kHz

(using averaged 1/3 octave analysis)

Chirp Source

Time record Continuous or burst

Output Sine sweep across the FFT span Flatness ±0.25 dBpp (amplitude: 1.0 Vp)

Swept-Sine Source

Auto functions Source level, input range and

frequency resolution

Dynamic range 145 dB

Arbitrary Source

Amplitude range $\pm 5 \text{ V}$

Record length 2 Msamples (playback from arbitrary

waveform memory or capture buffer),

variable sample rate

General

Disk drive

CRT monitor Monochrome, $800H \times 600V$ resolution

Interfaces IEEE-488.2, RS-232 and printer

interfaces standard. All instrument functions can be controlled through the computer interfaces. A PC (XT)

keyboard input is provided for

additional flexibility.

Hardcopy Print to dot matrix and PCL

compatible printers. Plot to HP-GL or postscript plotters. Print/Plot to RS-232 or IEEE-488.2 interfaces or to disk file. Additional file formats include GIF, PCX and EPS.

3.5" DOS format, 1.44 MB. Storage

of displays, setups and hardcopy.

Preamp Power Power connector for SRS preamps Power 70 W, 100/120/220/240 VAC,

50/60 Hz

Dimensions $17" \times 8.25" \times 24"$ (WHD)

Weight 56 lbs.

Warranty One year parts and labor on defects

in materials and workmanship

